

The World Leader in Elemental & Isotopic Microanalysis

The CAMECA instruments use complementary analytical techniques to deliver high sensitivity, high precision analyses, allowing researchers and engineers to gain a deeper understanding of the properties of materials.

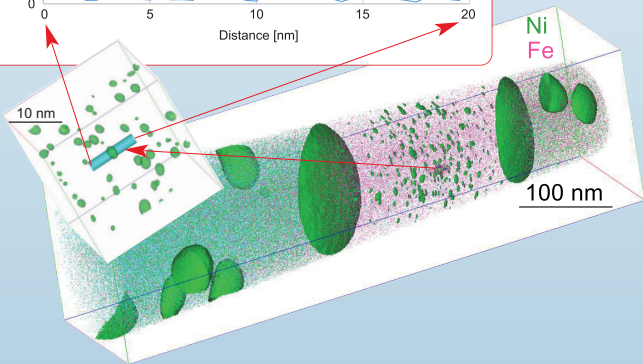
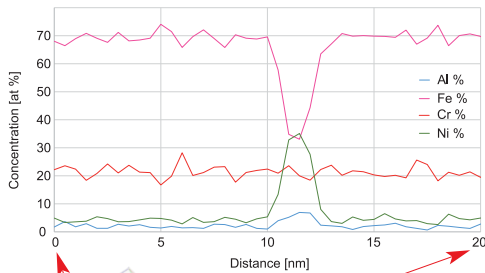
EIKOS™ Atom Probe

The Atom Probe for Research & Industry



EIKOS delivers nanoscale structural information allowing cost-effective alloy development and materials research.

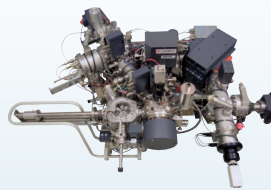
Analysis of an iron-based superalloy with EIKOS Atom Probe demonstrating microscale imaging capabilities with nanoscale chemical resolution.



Also in our APT product line, the LEAP® 5000 achieves up to 80% ion efficiency on oxides, ceramics, semiconductors...

IMS 7f-Auto

High Throughput, Versatile SIMS



The IMS 7f-Auto is the latest version of our successful IMS xf Secondary Ion Mass Spectrometer (SIMS) product line. Designed to deliver high precision elemental and isotopic analyses with increased ease-of-use and productivity, it has been optimized for challenging applications such as glass, metals, ceramics, semiconductors, thin films...

Attom ES

Enhanced Sensitivity High Resolution ICP-MS



The Attom ES Laser Ablation Inductively Coupled Plasma Mass Spectrometer from Nu is designed to be the ultimate tool for rapid and precise isotope ratio and quantitative analysis of trace elements.

Astrum

High Resolution Glow Discharge Mass Spectrometer



Astrum identifies impurities in materials with excellent detection limits. Applications range from nickel superalloys for aerospace to copper and silicon for semiconductors.